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Understanding **Embedded - FPGAs (Field Programmable Gate Array)**

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details

Product Status	Active
Number of LABs/CLBs	160
Number of Logic Elements/Cells	1280
Total RAM Bits	75776
Number of I/O	206
Number of Gates	-
Voltage - Supply	2.375V ~ 3.465V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	256-LBGA
Supplier Device Package	256-FTBGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lcmxo2-1200uhc-4ftg256c

Figure 2-8. sysMEM Memory Primitives

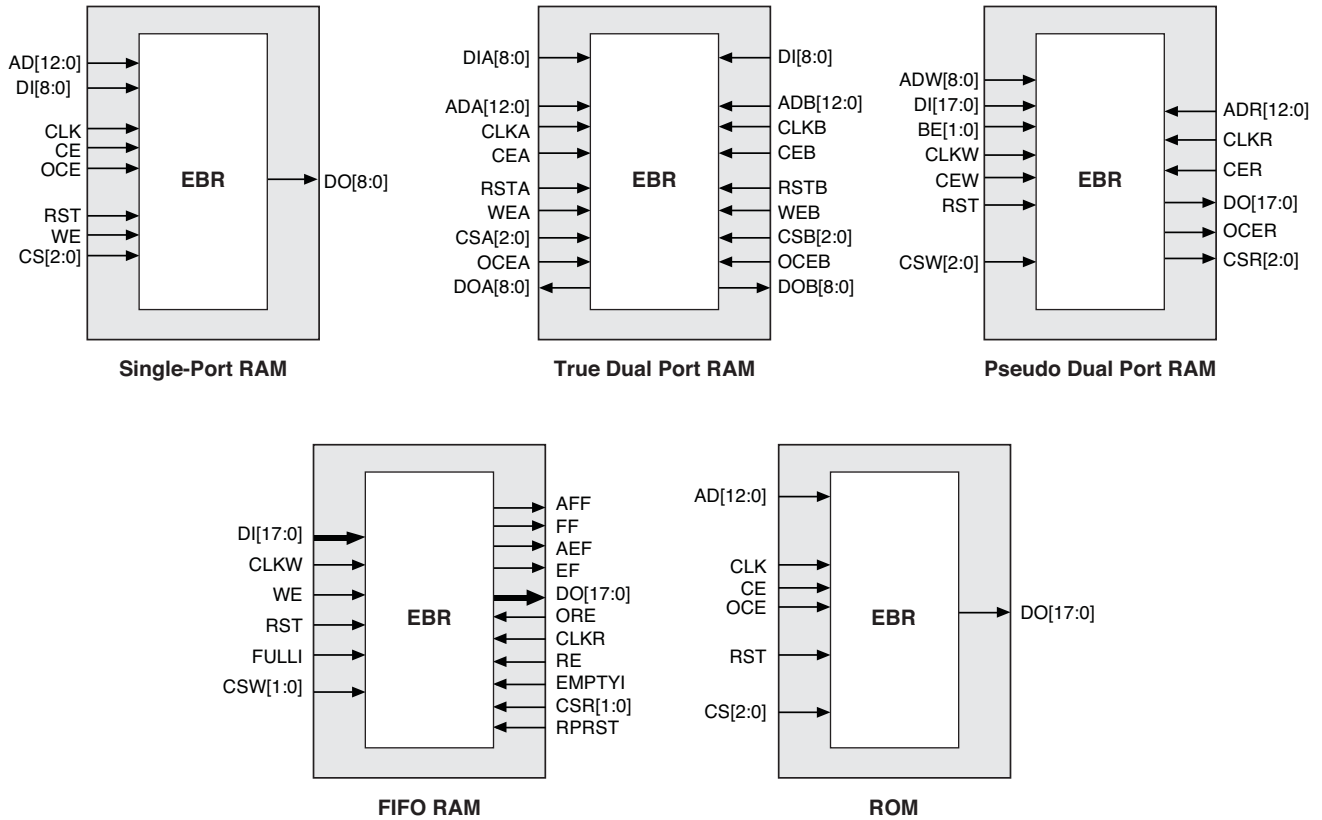
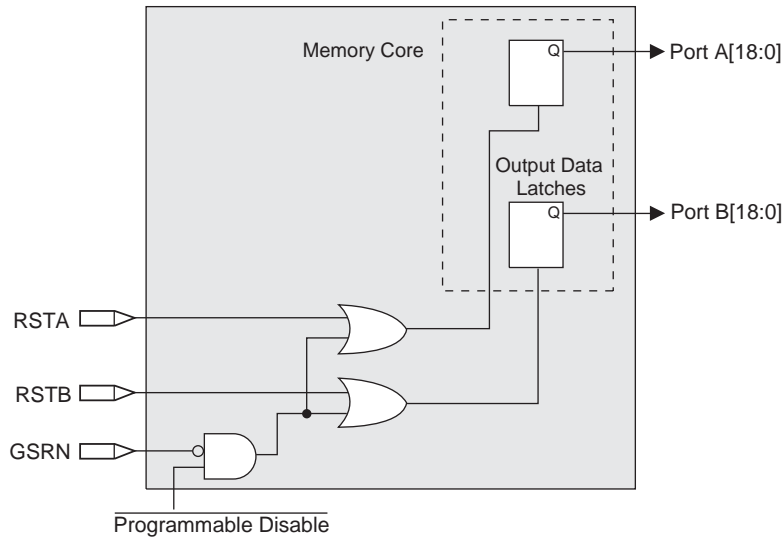


Table 2-6. EBR Signal Descriptions

Port Name	Description	Active State
CLK	Clock	Rising Clock Edge
CE	Clock Enable	Active High
OCE ¹	Output Clock Enable	Active High
RST	Reset	Active High
BE ¹	Byte Enable	Active High
WE	Write Enable	Active High
AD	Address Bus	—
DI	Data In	—
DO	Data Out	—
CS	Chip Select	Active High
AFF	FIFO RAM Almost Full Flag	—
FF	FIFO RAM Full Flag	—
AEF	FIFO RAM Almost Empty Flag	—
EF	FIFO RAM Empty Flag	—
RPRST	FIFO RAM Read Pointer Reset	—

1. Optional signals.
2. For dual port EBR primitives a trailing 'A' or 'B' in the signal name specifies the EBR port A or port B respectively.
3. For FIFO RAM mode primitive, a trailing 'R' or 'W' in the signal name specifies the FIFO read port or write port respectively.
4. For FIFO RAM mode primitive FULLI has the same function as CSW(2) and EMPTYI has the same function as CSR(2).
5. In FIFO mode, CLKW is the write port clock, CSW is the write port chip select, CLKR is the read port clock, CSR is the read port chip select, ORE is the output read enable.

Figure 2-9. Memory Core Reset

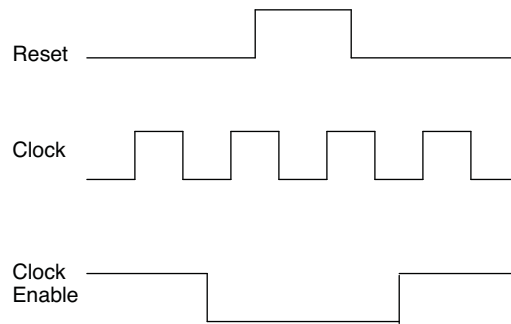


For further information on the sysMEM EBR block, please refer to TN1201, [Memory Usage Guide for MachXO2 Devices](#).

EBR Asynchronous Reset

EBR asynchronous reset or GSR (if used) can only be applied if all clock enables are low for a clock cycle before the reset is applied and released a clock cycle after the reset is released, as shown in Figure 2-10. The GSR input to the EBR is always asynchronous.

Figure 2-10. EBR Asynchronous Reset (Including GSR) Timing Diagram



If all clock enables remain enabled, the EBR asynchronous reset or GSR may only be applied and released after the EBR read and write clock inputs are in a steady state condition for a minimum of $1/f_{MAX}$ (EBR clock). The reset release must adhere to the EBR synchronous reset setup time before the next active read or write clock edge.

If an EBR is pre-loaded during configuration, the GSR input must be disabled or the release of the GSR during device wake up must occur before the release of the device I/Os becoming active.

These instructions apply to all EBR RAM, ROM and FIFO implementations. For the EBR FIFO mode, the GSR signal is always enabled and the WE and RE signals act like the clock enable signals in Figure 2-10. The reset timing rules apply to the RPRreset input versus the RE input and the RST input versus the WE and RE inputs. Both RST and RPRreset are always asynchronous EBR inputs. For more details refer to TN1201, [Memory Usage Guide for MachXO2 Devices](#).

Note that there are no reset restrictions if the EBR synchronous reset is used and the EBR GSR input is disabled.

MachXO2-640U, MachXO2-1200/U, MachXO2-2000/U, MachXO2-4000 and MachXO2-7000 devices contain three types of sysIO buffer pairs.

1. Left and Right sysIO Buffer Pairs

The sysIO buffer pairs in the left and right banks of the device consist of two single-ended output drivers and two single-ended input buffers (for ratioed inputs such as LVCMOS and LVTTL). The I/O pairs on the left and right of the devices also have differential and referenced input buffers.

2. Bottom sysIO Buffer Pairs

The sysIO buffer pairs in the bottom bank of the device consist of two single-ended output drivers and two single-ended input buffers (for ratioed inputs such as LVCMOS and LVTTL). The I/O pairs on the bottom also have differential and referenced input buffers. Only the I/Os on the bottom banks have programmable PCI clamps and differential input termination. The PCI clamp is enabled after V_{CC} and V_{CCIO} are at valid operating levels and the device has been configured.

3. Top sysIO Buffer Pairs

The sysIO buffer pairs in the top bank of the device consist of two single-ended output drivers and two single-ended input buffers (for ratioed inputs such as LVCMOS and LVTTL). The I/O pairs on the top also have differential and referenced I/O buffers. Half of the sysIO buffer pairs on the top edge have true differential outputs. The sysIO buffer pair comprising of the A and B PIOs in every PIC on the top edge have a differential output driver. The referenced input buffer can also be configured as a differential input buffer.

Typical I/O Behavior During Power-up

The internal power-on-reset (POR) signal is deactivated when V_{CC} and V_{CCIO0} have reached V_{PORUP} level defined in the Power-On-Reset Voltage table in the DC and Switching Characteristics section of this data sheet. After the POR signal is deactivated, the FPGA core logic becomes active. It is the user's responsibility to ensure that all V_{CCIO} banks are active with valid input logic levels to properly control the output logic states of all the I/O banks that are critical to the application. The default configuration of the I/O pins in a blank device is tri-state with a weak pull-down to GND (some pins such as PROGRAMN and the JTAG pins have weak pull-up to V_{CCIO} as the default functionality). The I/O pins will maintain the blank configuration until V_{CC} and V_{CCIO} (for I/O banks containing configuration I/Os) have reached V_{PORUP} levels at which time the I/Os will take on the user-configured settings only after a proper download/configuration.

Supported Standards

The MachXO2 sysIO buffer supports both single-ended and differential standards. Single-ended standards can be further subdivided into LVCMOS, LVTTL, and PCI. The buffer supports the LVTTL, PCI, LVCMOS 1.2, 1.5, 1.8, 2.5, and 3.3 V standards. In the LVCMOS and LVTTL modes, the buffer has individually configurable options for drive strength, bus maintenance (weak pull-up, weak pull-down, bus-keeper latch or none) and open drain. BLVDS, MLVDS and LVPECL output emulation is supported on all devices. The MachXO2-640U, MachXO2-1200/U and higher devices support on-chip LVDS output buffers on approximately 50% of the I/Os on the top bank. Differential receivers for LVDS, BLVDS, MLVDS and LVPECL are supported on all banks of MachXO2 devices. PCI support is provided in the bottom bank of the MachXO2-640U, MachXO2-1200/U and higher density devices. Table 2-11 summarizes the I/O characteristics of the MachXO2 PLDs.

Tables 2-11 and 2-12 show the I/O standards (together with their supply and reference voltages) supported by the MachXO2 devices. For further information on utilizing the sysIO buffer to support a variety of standards please see TN1202, [MachXO2 sysIO Usage Guide](#).

Configuration and Testing

This section describes the configuration and testing features of the MachXO2 family.

IEEE 1149.1-Compliant Boundary Scan Testability

All MachXO2 devices have boundary scan cells that are accessed through an IEEE 1149.1 compliant test access port (TAP). This allows functional testing of the circuit board, on which the device is mounted, through a serial scan path that can access all critical logic nodes. Internal registers are linked internally, allowing test data to be shifted in and loaded directly onto test nodes, or test data to be captured and shifted out for verification. The test access port consists of dedicated I/Os: TDI, TDO, TCK and TMS. The test access port shares its power supply with V_{CCIO} Bank 0 and can operate with LVCMOS3.3, 2.5, 1.8, 1.5, and 1.2 standards.

For more details on boundary scan test, see AN8066, [Boundary Scan Testability with Lattice sysIO Capability](#) and TN1087, [Minimizing System Interruption During Configuration Using TransFR Technology](#).

Device Configuration

All MachXO2 devices contain two ports that can be used for device configuration. The Test Access Port (TAP), which supports bit-wide configuration and the sysCONFIG port which supports serial configuration through I²C or SPI. The TAP supports both the IEEE Standard 1149.1 Boundary Scan specification and the IEEE Standard 1532 In-System Configuration specification. There are various ways to configure a MachXO2 device:

1. Internal Flash Download
2. JTAG
3. Standard Serial Peripheral Interface (Master SPI mode) – interface to boot PROM memory
4. System microprocessor to drive a serial slave SPI port (SSPI mode)
5. Standard I²C Interface to system microprocessor

Upon power-up, the configuration SRAM is ready to be configured using the selected sysCONFIG port. Once a configuration port is selected, it will remain active throughout that configuration cycle. The IEEE 1149.1 port can be activated any time after power-up by sending the appropriate command through the TAP port. Optionally the device can run a CRC check upon entering the user mode. This will ensure that the device was configured correctly.

The sysCONFIG port has 10 dual-function pins which can be used as general purpose I/Os if they are not required for configuration. See TN1204, [MachXO2 Programming and Configuration Usage Guide](#) for more information about using the dual-use pins as general purpose I/Os.

Lattice design software uses proprietary compression technology to compress bit-streams for use in MachXO2 devices. Use of this technology allows Lattice to provide a lower cost solution. In the unlikely event that this technology is unable to compress bitstreams to fit into the amount of on-chip Flash memory, there are a variety of techniques that can be utilized to allow the bitstream to fit in the on-chip Flash memory. For more details, refer to TN1204, [MachXO2 Programming and Configuration Usage Guide](#).

The Test Access Port (TAP) has five dual purpose pins (TDI, TDO, TMS, TCK and JTAGENB). These pins are dual function pins - TDI, TDO, TMS and TCK can be used as general purpose I/O if desired. For more details, refer to TN1204, [MachXO2 Programming and Configuration Usage Guide](#).

TransFR (Transparent Field Reconfiguration)

TransFR is a unique Lattice technology that allows users to update their logic in the field without interrupting system operation using a simple push-button solution. For more details refer to TN1087, [Minimizing System Interruption During Configuration Using TransFR Technology](#) for details.

DC Electrical Characteristics

Over Recommended Operating Conditions

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
$I_{IL}, I_{IH}^{1,4}$	Input or I/O Leakage	Clamp OFF and $V_{CCIO} < V_{IN} < V_{IH} (MAX)$	—	—	+175	μA
		Clamp OFF and $V_{IN} = V_{CCIO}$	-10	—	10	μA
		Clamp OFF and $V_{CCIO} - 0.97 V < V_{IN} < V_{CCIO}$	-175	—	—	μA
		Clamp OFF and $0 V < V_{IN} < V_{CCIO} - 0.97 V$	—	—	10	μA
		Clamp OFF and $V_{IN} = GND$	—	—	10	μA
		Clamp ON and $0 V < V_{IN} < V_{CCIO}$	—	—	10	μA
I_{PU}	I/O Active Pull-up Current	$0 < V_{IN} < 0.7 V_{CCIO}$	-30	—	-309	μA
I_{PD}	I/O Active Pull-down Current	$V_{IL} (MAX) < V_{IN} < V_{CCIO}$	30	—	305	μA
I_{BHLS}	Bus Hold Low sustaining current	$V_{IN} = V_{IL} (MAX)$	30	—	—	μA
I_{BHHS}	Bus Hold High sustaining current	$V_{IN} = 0.7V_{CCIO}$	-30	—	—	μA
I_{BHLO}	Bus Hold Low Overdrive current	$0 \leq V_{IN} \leq V_{CCIO}$	—	—	305	μA
I_{BHHO}	Bus Hold High Overdrive current	$0 \leq V_{IN} \leq V_{CCIO}$	—	—	-309	μA
V_{BHT}^3	Bus Hold Trip Points		$V_{IL} (MAX)$	—	$V_{IH} (MIN)$	V
C1	I/O Capacitance ²	$V_{CCIO} = 3.3 V, 2.5 V, 1.8 V, 1.5 V, 1.2 V, V_{CC} = Typ., V_{IO} = 0 \text{ to } V_{IH} (MAX)$	3	5	9	pF
C2	Dedicated Input Capacitance ²	$V_{CCIO} = 3.3 V, 2.5 V, 1.8 V, 1.5 V, 1.2 V, V_{CC} = Typ., V_{IO} = 0 \text{ to } V_{IH} (MAX)$	3	5.5	7	pF
V_{HYST}	Hysteresis for Schmitt Trigger Inputs ⁵	$V_{CCIO} = 3.3 V, \text{Hysteresis} = \text{Large}$	—	450	—	mV
		$V_{CCIO} = 2.5 V, \text{Hysteresis} = \text{Large}$	—	250	—	mV
		$V_{CCIO} = 1.8 V, \text{Hysteresis} = \text{Large}$	—	125	—	mV
		$V_{CCIO} = 1.5 V, \text{Hysteresis} = \text{Large}$	—	100	—	mV
		$V_{CCIO} = 3.3 V, \text{Hysteresis} = \text{Small}$	—	250	—	mV
		$V_{CCIO} = 2.5 V, \text{Hysteresis} = \text{Small}$	—	150	—	mV
		$V_{CCIO} = 1.8 V, \text{Hysteresis} = \text{Small}$	—	60	—	mV
		$V_{CCIO} = 1.5 V, \text{Hysteresis} = \text{Small}$	—	40	—	mV

1. Input or I/O leakage current is measured with the pin configured as an input or as an I/O with the output driver tri-stated. It is not measured with the output driver active. Bus maintenance circuits are disabled.
2. T_A 25 °C, $f = 1.0$ MHz.
3. Please refer to V_{IL} and V_{IH} in the sysIO Single-Ended DC Electrical Characteristics table of this document.
4. When V_{IH} is higher than V_{CCIO} , a transient current typically of 30 ns in duration or less with a peak current of 6 mA can occur on the high-to-low transition. For true LVDS output pins in MachXO2-640U, MachXO2-1200/U and larger devices, V_{IH} must be less than or equal to V_{CCIO} .
5. With bus keeper circuit turned on. For more details, refer to TN1202, [MachXO2 sysIO Usage Guide](#).

BLVDS

The MachXO2 family supports the BLVDS standard through emulation. The output is emulated using complementary LVCMOS outputs in conjunction with resistors across the driver outputs. The input standard is supported by the LVDS differential input buffer. BLVDS is intended for use when multi-drop and bi-directional multi-point differential signaling is required. The scheme shown in Figure 3-2 is one possible solution for bi-directional multi-point differential signals.

Figure 3-2. BLVDS Multi-point Output Example

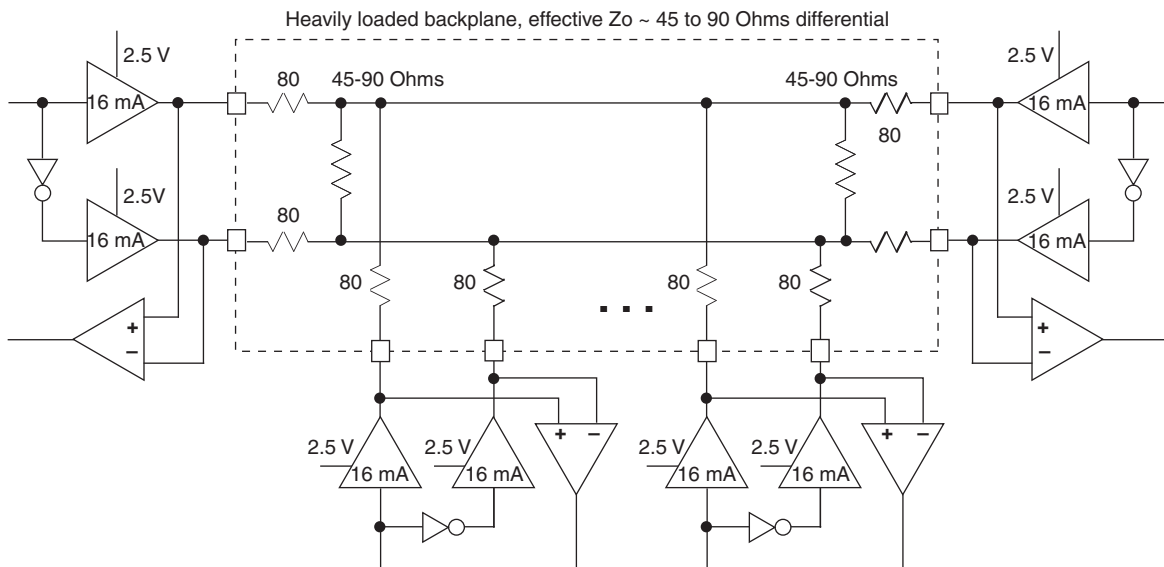


Table 3-2. BLVDS DC Conditions¹

Over Recommended Operating Conditions

Symbol	Description	Nominal		Units
		Zo = 45	Zo = 90	
Z _{OUT}	Output impedance	20	20	Ohms
R _S	Driver series resistance	80	80	Ohms
R _{TLEFT}	Left end termination	45	90	Ohms
R _{TRIGHT}	Right end termination	45	90	Ohms
V _{OH}	Output high voltage	1.376	1.480	V
V _{OL}	Output low voltage	1.124	1.020	V
V _{OD}	Output differential voltage	0.253	0.459	V
V _{CM}	Output common mode voltage	1.250	1.250	V
I _{DC}	DC output current	11.236	10.204	mA

1. For input buffer, see LVDS table.

RSDS

The MachXO2 family supports the differential RSDS standard. The output standard is emulated using complementary LVCMOS outputs in conjunction with resistors across the driver outputs on all the devices. The RSDS input standard is supported by the LVDS differential input buffer. The scheme shown in Figure 3-4 is one possible solution for RSDS standard implementation. Use LVDS25E mode with suggested resistors for RSDS operation. Resistor values in Figure 3-4 are industry standard values for 1% resistors.

Figure 3-4. RSDS (Reduced Swing Differential Standard)

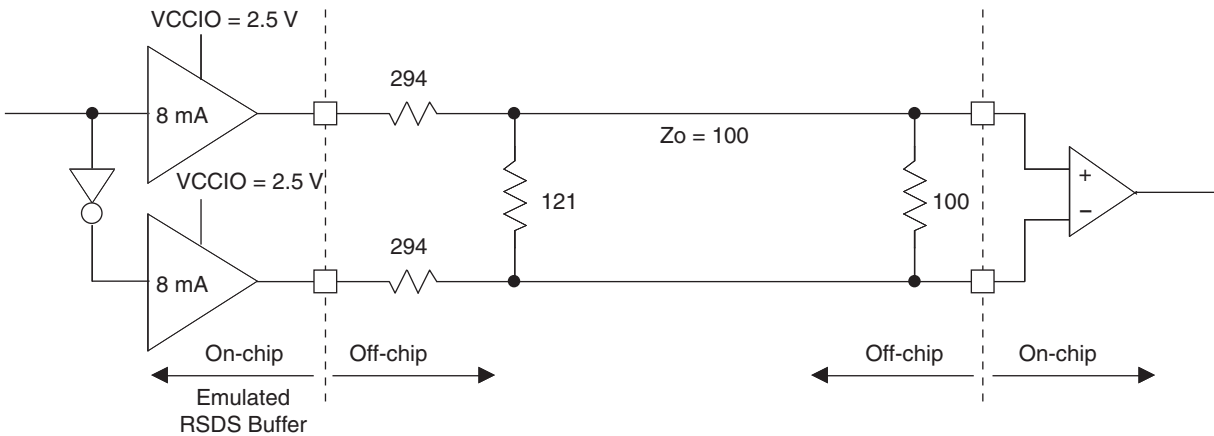


Table 3-4. RSDS DC Conditions

Parameter	Description	Typical	Units
Z_{OUT}	Output impedance	20	Ohms
R_S	Driver series resistor	294	Ohms
R_P	Driver parallel resistor	121	Ohms
R_T	Receiver termination	100	Ohms
V_{OH}	Output high voltage	1.35	V
V_{OL}	Output low voltage	1.15	V
V_{OD}	Output differential voltage	0.20	V
V_{CM}	Output common mode voltage	1.25	V
Z_{BACK}	Back impedance	101.5	Ohms
I_{DC}	DC output current	3.66	mA

Typical Building Block Function Performance – ZE Devices¹

Pin-to-Pin Performance (LVCMOS25 12 mA Drive)

Function	-3 Timing	Units
Basic Functions		
16-bit decoder	13.9	ns
4:1 MUX	10.9	ns
16:1 MUX	12.0	ns

Register-to-Register Performance

Function	-3 Timing	Units
Basic Functions		
16:1 MUX	191	MHz
16-bit adder	134	MHz
16-bit counter	148	MHz
64-bit counter	77	MHz
Embedded Memory Functions		
1024x9 True-Dual Port RAM (Write Through or Normal, EBR output registers)	90	MHz
Distributed Memory Functions		
16x4 Pseudo-Dual Port RAM (one PFU)	214	MHz

1. The above timing numbers are generated using the Diamond design tool. Exact performance may vary with device and tool version. The tool uses internal parameters that have been characterized but are not tested on every device.

Derating Logic Timing

Logic timing provided in the following sections of the data sheet and the Lattice design tools are worst case numbers in the operating range. Actual delays may be much faster. Lattice design tools can provide logic timing numbers at a particular temperature and voltage.

MachXO2 External Switching Characteristics – HC/HE Devices^{1, 2, 3, 4, 5, 6, 7}

Over Recommended Operating Conditions

Parameter	Description	Device	-6		-5		-4		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
Clocks									
Primary Clocks									
$f_{MAX_PRI}^8$	Frequency for Primary Clock Tree	All MachXO2 devices	—	388	—	323	—	269	MHz
t_{W_PRI}	Clock Pulse Width for Primary Clock	All MachXO2 devices	0.5	—	0.6	—	0.7	—	ns
t_{SKEW_PRI}	Primary Clock Skew Within a Device	MachXO2-256HC-HE	—	912	—	939	—	975	ps
		MachXO2-640HC-HE	—	844	—	871	—	908	ps
		MachXO2-1200HC-HE	—	868	—	902	—	951	ps
		MachXO2-2000HC-HE	—	867	—	897	—	941	ps
		MachXO2-4000HC-HE	—	865	—	892	—	931	ps
		MachXO2-7000HC-HE	—	902	—	942	—	989	ps
Edge Clock									
$f_{MAX_EDGE}^8$	Frequency for Edge Clock	MachXO2-1200 and larger devices	—	400	—	333	—	278	MHz
Pin-LUT-Pin Propagation Delay									
t_{PD}	Best case propagation delay through one LUT-4	All MachXO2 devices	—	6.72	—	6.96	—	7.24	ns
General I/O Pin Parameters (Using Primary Clock without PLL)									
t_{CO}	Clock to Output – PIO Output Register	MachXO2-256HC-HE	—	7.13	—	7.30	—	7.57	ns
		MachXO2-640HC-HE	—	7.15	—	7.30	—	7.57	ns
		MachXO2-1200HC-HE	—	7.44	—	7.64	—	7.94	ns
		MachXO2-2000HC-HE	—	7.46	—	7.66	—	7.96	ns
		MachXO2-4000HC-HE	—	7.51	—	7.71	—	8.01	ns
		MachXO2-7000HC-HE	—	7.54	—	7.75	—	8.06	ns
t_{SU}	Clock to Data Setup – PIO Input Register	MachXO2-256HC-HE	-0.06	—	-0.06	—	-0.06	—	ns
		MachXO2-640HC-HE	-0.06	—	-0.06	—	-0.06	—	ns
		MachXO2-1200HC-HE	-0.17	—	-0.17	—	-0.17	—	ns
		MachXO2-2000HC-HE	-0.20	—	-0.20	—	-0.20	—	ns
		MachXO2-4000HC-HE	-0.23	—	-0.23	—	-0.23	—	ns
		MachXO2-7000HC-HE	-0.23	—	-0.23	—	-0.23	—	ns
t_H	Clock to Data Hold – PIO Input Register	MachXO2-256HC-HE	1.75	—	1.95	—	2.16	—	ns
		MachXO2-640HC-HE	1.75	—	1.95	—	2.16	—	ns
		MachXO2-1200HC-HE	1.88	—	2.12	—	2.36	—	ns
		MachXO2-2000HC-HE	1.89	—	2.13	—	2.37	—	ns
		MachXO2-4000HC-HE	1.94	—	2.18	—	2.43	—	ns
		MachXO2-7000HC-HE	1.98	—	2.23	—	2.49	—	ns

Parameter	Description	Device	-6		-5		-4		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
Generic DDRX2 Outputs with Clock and Data Centered at Pin Using PCLK Pin for Clock Input – GDDR2_TX.ECLK.Centered^{9, 12}									
t _{DVB}	Output Data Valid Before CLK Output	MachXO2-640U, MachXO2-1200/U and larger devices, top side only.	0.535	—	0.670	—	0.830	—	ns
t _{DVA}	Output Data Valid After CLK Output		0.535	—	0.670	—	0.830	—	ns
f _{DATA}	DDR2 Serial Output Data Speed		—	664	—	554	—	462	Mbps
f _{DDR2}	DDR2 ECLK Frequency (minimum limited by PLL)		—	332	—	277	—	231	MHz
f _{SCLK}	SCLK Frequency		—	166	—	139	—	116	MHz
Generic DDRX4 Outputs with Clock and Data Aligned at Pin Using PCLK Pin for Clock Input – GDDR4_TX.ECLK.Aligned^{9, 12}									
t _{DIA}	Output Data Invalid After CLK Output	MachXO2-640U, MachXO2-1200/U and larger devices, top side only.	—	0.200	—	0.215	—	0.230	ns
t _{DIB}	Output Data Invalid Before CLK Output		—	0.200	—	0.215	—	0.230	ns
f _{DATA}	DDR4 Serial Output Data Speed		—	756	—	630	—	524	Mbps
f _{DDR4}	DDR4 ECLK Frequency		—	378	—	315	—	262	MHz
f _{SCLK}	SCLK Frequency		—	95	—	79	—	66	MHz
Generic DDRX4 Outputs with Clock and Data Centered at Pin Using PCLK Pin for Clock Input – GDDR4_TX.ECLK.Centered^{9, 12}									
t _{DVB}	Output Data Valid Before CLK Output	MachXO2-640U, MachXO2-1200/U and larger devices, top side only.	0.455	—	0.570	—	0.710	—	ns
t _{DVA}	Output Data Valid After CLK Output		0.455	—	0.570	—	0.710	—	ns
f _{DATA}	DDR4 Serial Output Data Speed		—	756	—	630	—	524	Mbps
f _{DDR4}	DDR4 ECLK Frequency (minimum limited by PLL)		—	378	—	315	—	262	MHz
f _{SCLK}	SCLK Frequency		—	95	—	79	—	66	MHz
7:1 LVDS Outputs – GDDR71_TX.ECLK.7:1^{9, 12}									
t _{DIB}	Output Data Invalid Before CLK Output	MachXO2-640U, MachXO2-1200/U and larger devices, top side only.	—	0.160	—	0.180	—	0.200	ns
t _{DIA}	Output Data Invalid After CLK Output		—	0.160	—	0.180	—	0.200	ns
f _{DATA}	DDR71 Serial Output Data Speed		—	756	—	630	—	524	Mbps
f _{DDR71}	DDR71 ECLK Frequency		—	378	—	315	—	262	MHz
f _{CLKOUT}	7:1 Output Clock Frequency (SCLK) (minimum limited by PLL)		—	108	—	90	—	75	MHz

Parameter	Description	Device	-3		-2		-1		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
t _{HPLL}	Clock to Data Hold – PIO Input Register	MachXO2-1200ZE	0.66	—	0.68	—	0.80	—	ns
		MachXO2-2000ZE	0.68	—	0.70	—	0.83	—	ns
		MachXO2-4000ZE	0.68	—	0.71	—	0.84	—	ns
		MachXO2-7000ZE	0.73	—	0.74	—	0.87	—	ns
t _{SU_DELPLL}	Clock to Data Setup – PIO Input Register with Data Input Delay	MachXO2-1200ZE	5.14	—	5.69	—	6.20	—	ns
		MachXO2-2000ZE	5.11	—	5.67	—	6.17	—	ns
		MachXO2-4000ZE	5.27	—	5.84	—	6.35	—	ns
		MachXO2-7000ZE	5.15	—	5.71	—	6.23	—	ns
t _{H_DELPLL}	Clock to Data Hold – PIO Input Register with Input Data Delay	MachXO2-1200ZE	-1.36	—	-1.36	—	-1.36	—	ns
		MachXO2-2000ZE	-1.35	—	-1.35	—	-1.35	—	ns
		MachXO2-4000ZE	-1.43	—	-1.43	—	-1.43	—	ns
		MachXO2-7000ZE	-1.41	—	-1.41	—	-1.41	—	ns
Generic DDRX1 Inputs with Clock and Data Aligned at Pin Using PCLK Pin for Clock Input – GDDR1_RX.SCLK.Aligned^{9,12}									
t _{DVA}	Input Data Valid After CLK	All MachXO2 devices, all sides	—	0.382	—	0.401	—	0.417	UI
t _{DVE}	Input Data Hold After CLK		0.670	—	0.684	—	0.693	—	UI
f _{DATA}	DDR1 Input Data Speed		—	140	—	116	—	98	Mbps
f _{DDR1}	DDR1 SCLK Frequency		—	70	—	58	—	49	MHz
Generic DDRX1 Inputs with Clock and Data Centered at Pin Using PCLK Pin for Clock Input – GDDR1_RX.SCLK.Centered^{9,12}									
t _{SU}	Input Data Setup Before CLK	All MachXO2 devices, all sides	1.319	—	1.412	—	1.462	—	ns
t _{HO}	Input Data Hold After CLK		0.717	—	1.010	—	1.340	—	ns
f _{DATA}	DDR1 Input Data Speed		—	140	—	116	—	98	Mbps
f _{DDR1}	DDR1 SCLK Frequency		—	70	—	58	—	49	MHz
Generic DDRX2 Inputs with Clock and Data Aligned at Pin Using PCLK Pin for Clock Input – GDDR2_RX.ECLK.Aligned^{9,12}									
t _{DVA}	Input Data Valid After CLK	MachXO2-640U, MachXO2-1200/U and larger devices, bottom side only ¹¹	—	0.361	—	0.346	—	0.334	UI
t _{DVE}	Input Data Hold After CLK		0.602	—	0.625	—	0.648	—	UI
f _{DATA}	DDR2 Serial Input Data Speed		—	280	—	234	—	194	Mbps
f _{DDR2}	DDR2 ECLK Frequency		—	140	—	117	—	97	MHz
f _{SCLK}	SCLK Frequency		—	70	—	59	—	49	MHz
Generic DDRX2 Inputs with Clock and Data Centered at Pin Using PCLK Pin for Clock Input – GDDR2_RX.ECLK.Centered^{9,12}									
t _{SU}	Input Data Setup Before CLK	MachXO2-640U, MachXO2-1200/U and larger devices, bottom side only ¹¹	0.472	—	0.672	—	0.865	—	ns
t _{HO}	Input Data Hold After CLK		0.363	—	0.501	—	0.743	—	ns
f _{DATA}	DDR2 Serial Input Data Speed		—	280	—	234	—	194	Mbps
f _{DDR2}	DDR2 ECLK Frequency		—	140	—	117	—	97	MHz
f _{SCLK}	SCLK Frequency		—	70	—	59	—	49	MHz
Generic DDR4 Inputs with Clock and Data Aligned at Pin Using PCLK Pin for Clock Input - GDDR4_RX.ECLK.Aligned^{9,12}									
t _{DVA}	Input Data Valid After ECLK	MachXO2-640U, MachXO2-1200/U and larger devices, bottom side only ¹¹	—	0.307	—	0.316	—	0.326	UI
t _{DVE}	Input Data Hold After ECLK		0.662	—	0.650	—	0.649	—	UI
f _{DATA}	DDR4 Serial Input Data Speed		—	420	—	352	—	292	Mbps
f _{DDR4}	DDR4 ECLK Frequency		—	210	—	176	—	146	MHz
f _{SCLK}	SCLK Frequency		—	53	—	44	—	37	MHz

Parameter	Description	Device	-3		-2		-1		Units
			Min.	Max.	Min.	Max.	Min.	Max.	
LPDDR^{9, 12}									
t _{DVADQ}	Input Data Valid After DQS Input	MachXO2-1200/U and larger devices, right side only. ¹³	—	0.349	—	0.381	—	0.396	UI
t _{DVEDQ}	Input Data Hold After DQS Input		0.665	—	0.630	—	0.613	—	UI
t _{DQVBS}	Output Data Invalid Before DQS Output		0.25	—	0.25	—	0.25	—	UI
t _{DQVAS}	Output Data Invalid After DQS Output		0.25	—	0.25	—	0.25	—	UI
f _{DATA}	MEM LPDDR Serial Data Speed		—	120	—	110	—	96	Mbps
f _{SCLK}	SCLK Frequency		—	60	—	55	—	48	MHz
f _{LPDDR}	LPDDR Data Transfer Rate		0	120	0	110	0	96	Mbps
DDR^{9, 12}									
t _{DVADQ}	Input Data Valid After DQS Input	MachXO2-1200/U and larger devices, right side only. ¹³	—	0.347	—	0.374	—	0.393	UI
t _{DVEDQ}	Input Data Hold After DQS Input		0.665	—	0.637	—	0.616	—	UI
t _{DQVBS}	Output Data Invalid Before DQS Output		0.25	—	0.25	—	0.25	—	UI
t _{DQVAS}	Output Data Invalid After DQS Output		0.25	—	0.25	—	0.25	—	UI
f _{DATA}	MEM DDR Serial Data Speed		—	140	—	116	—	98	Mbps
f _{SCLK}	SCLK Frequency		—	70	—	58	—	49	MHz
f _{MEM_DDR}	MEM DDR Data Transfer Rate		N/A	140	N/A	116	N/A	98	Mbps
DDR2^{9, 12}									
t _{DVADQ}	Input Data Valid After DQS Input	MachXO2-1200/U and larger devices, right side only. ¹³	—	0.372	—	0.394	—	0.410	UI
t _{DVEDQ}	Input Data Hold After DQS Input		0.690	—	0.658	—	0.618	—	UI
t _{DQVBS}	Output Data Invalid Before DQS Output		0.25	—	0.25	—	0.25	—	UI
t _{DQVAS}	Output Data Invalid After DQS Output		0.25	—	0.25	—	0.25	—	UI
f _{DATA}	MEM DDR Serial Data Speed		—	140	—	116	—	98	Mbps
f _{SCLK}	SCLK Frequency		—	70	—	58	—	49	MHz
f _{MEM_DDR2}	MEM DDR2 Data Transfer Rate		N/A	140	N/A	116	N/A	98	Mbps

1. Exact performance may vary with device and design implementation. Commercial timing numbers are shown at 85 °C and 1.14 V. Other operating conditions, including industrial, can be extracted from the Diamond software.
2. General I/O timing numbers based on LVCMOS 2.5, 8 mA, 0 pf load, fast slew rate.
3. Generic DDR timing numbers based on LVDS I/O (for input, output, and clock ports).
4. DDR timing numbers based on SSTL25. DDR2 timing numbers based on SSTL18. LPDDR timing numbers based in LVCMOS18.
5. 7:1 LVDS (GDDR71) uses the LVDS I/O standard (for input, output, and clock ports).
6. For Generic DDRX1 mode $t_{SU} = t_{HO} = (t_{DVE} - t_{DVA} - 0.03 \text{ ns})/2$.
7. The t_{SU_DEL} and t_{H_DEL} values use the SCLK_ZERHOLD default step size. Each step is 167 ps (-3), 182 ps (-2), 195 ps (-1).
8. This number for general purpose usage. Duty cycle tolerance is +/-10%.
9. Duty cycle is +/- 5% for system usage.
10. The above timing numbers are generated using the Diamond design tool. Exact performance may vary with the device selected.
11. High-speed DDR and LVDS not supported in SG32 (32-Pin QFN) packages.
12. Advance information for MachXO2 devices in 48 QFN packages.
13. DDR memory interface not supported in QN84 (84 QFN) and SG32 (32 QFN) packages.

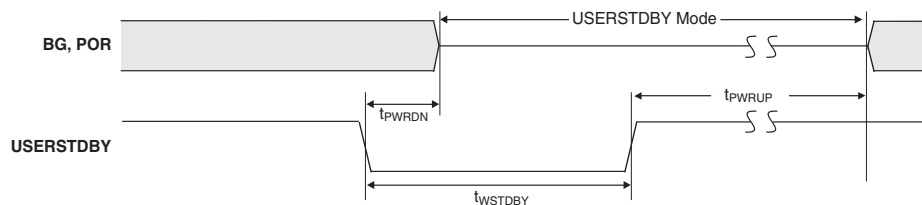
MachXO2 Oscillator Output Frequency

Symbol	Parameter	Min.	Typ.	Max	Units
f _{MAX}	Oscillator Output Frequency (Commercial Grade Devices, 0 to 85°C)	125.685	133	140.315	MHz
	Oscillator Output Frequency (Industrial Grade Devices, -40 °C to 100 °C)	124.355	133	141.645	MHz
t _{DT}	Output Clock Duty Cycle	43	50	57	%
t _{OPJIT} ¹	Output Clock Period Jitter	0.01	0.012	0.02	UIPP
t _{STABLEOSC}	STDBY Low to Oscillator Stable	0.01	0.05	0.1	µs

1. Output Clock Period Jitter specified at 133 MHz. The values for lower frequencies will be smaller UIPP. The typical value for 133 MHz is 95 ps and for 2.08 MHz the typical value is 1.54 ns.

MachXO2 Standby Mode Timing – HC/HE Devices

Symbol	Parameter	Device	Min.	Typ.	Max	Units
t _{PWRDN}	USERSTDBY High to Stop	All	—	—	9	ns
t _{PWRUP}	USERSTDBY Low to Power Up	LCMXO2-256		—		µs
		LCMXO2-640		—		µs
		LCMXO2-640U		—		µs
		LCMXO2-1200	20	—	50	µs
		LCMXO2-1200U		—		µs
		LCMXO2-2000		—		µs
		LCMXO2-2000U		—		µs
		LCMXO2-4000		—		µs
LCMXO2-7000		—		µs		
t _{WSTDBY}	USERSTDBY Pulse Width	All	18	—	—	ns



MachXO2 Standby Mode Timing – ZE Devices

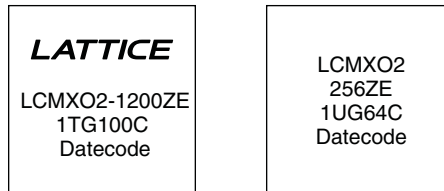
Symbol	Parameter	Device	Min.	Typ.	Max	Units
t _{PWRDN}	USERSTDBY High to Stop	All	—	—	13	ns
t _{PWRUP}	USERSTDBY Low to Power Up	LCMXO2-256		—		µs
		LCMXO2-640		—		µs
		LCMXO2-1200	20	—	50	µs
		LCMXO2-2000		—		µs
		LCMXO2-4000		—		µs
		LCMXO2-7000		—		µs
t _{WSTDBY}	USERSTDBY Pulse Width	All	19	—	—	ns
t _{BNDGAPSTBL}	USERSTDBY High to Bandgap Stable	All	—	—	15	ns

sysCONFIG Port Timing Specifications

Symbol	Parameter	Min.	Max.	Units	
All Configuration Modes					
t_{PRGM}	PROGRAMN low pulse accept	55	—	ns	
t_{PRGMJ}	PROGRAMN low pulse rejection	—	25	ns	
t_{INITL}	INITN low time	LCMXO2-256	—	30	μ s
		LCMXO2-640	—	35	μ s
		LCMXO2-640U/ LCMXO2-1200	—	55	μ s
		LCMXO2-1200U/ LCMXO2-2000	—	70	μ s
		LCMXO2-2000U/ LCMXO2-4000	—	105	μ s
		LCMXO2-7000	—	130	μ s
$t_{DPPINIT}$	PROGRAMN low to INITN low	—	150	ns	
$t_{DPPDONE}$	PROGRAMN low to DONE low	—	150	ns	
t_{IODISS}	PROGRAMN low to I/O disable	—	120	ns	
Slave SPI					
f_{MAX}	CCLK clock frequency	—	66	MHz	
t_{CCLKH}	CCLK clock pulse width high	7.5	—	ns	
t_{CCLKL}	CCLK clock pulse width low	7.5	—	ns	
t_{STSU}	CCLK setup time	2	—	ns	
t_{STH}	CCLK hold time	0	—	ns	
t_{STCO}	CCLK falling edge to valid output	—	10	ns	
t_{STOZ}	CCLK falling edge to valid disable	—	10	ns	
t_{STOV}	CCLK falling edge to valid enable	—	10	ns	
t_{SCS}	Chip select high time	25	—	ns	
t_{SCSS}	Chip select setup time	3	—	ns	
t_{SCSH}	Chip select hold time	3	—	ns	
Master SPI					
f_{MAX}	MCLK clock frequency	—	133	MHz	
t_{MCLKH}	MCLK clock pulse width high	3.75	—	ns	
t_{MCLKL}	MCLK clock pulse width low	3.75	—	ns	
t_{STSU}	MCLK setup time	5	—	ns	
t_{STH}	MCLK hold time	1	—	ns	
t_{CSSPI}	INITN high to chip select low	100	200	ns	
t_{MCLK}	INITN high to first MCLK edge	0.75	1	μ s	

Ordering Information

MachXO2 devices have top-side markings, for commercial and industrial grades, as shown below:



Notes:

1. Markings are abbreviated for small packages.
2. See [PCN 05A-12](#) for information regarding a change to the top-side mark logo.

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-7000HC-4TG144C	6864	2.5 V / 3.3 V	-4	Halogen-Free TQFP	144	COM
LCMXO2-7000HC-5TG144C	6864	2.5 V / 3.3 V	-5	Halogen-Free TQFP	144	COM
LCMXO2-7000HC-6TG144C	6864	2.5 V / 3.3 V	-6	Halogen-Free TQFP	144	COM
LCMXO2-7000HC-4BG256C	6864	2.5 V / 3.3 V	-4	Halogen-Free caBGA	256	COM
LCMXO2-7000HC-5BG256C	6864	2.5 V / 3.3 V	-5	Halogen-Free caBGA	256	COM
LCMXO2-7000HC-6BG256C	6864	2.5 V / 3.3 V	-6	Halogen-Free caBGA	256	COM
LCMXO2-7000HC-4FTG256C	6864	2.5 V / 3.3 V	-4	Halogen-Free ftBGA	256	COM
LCMXO2-7000HC-5FTG256C	6864	2.5 V / 3.3 V	-5	Halogen-Free ftBGA	256	COM
LCMXO2-7000HC-6FTG256C	6864	2.5 V / 3.3 V	-6	Halogen-Free ftBGA	256	COM
LCMXO2-7000HC-4BG332C	6864	2.5 V / 3.3 V	-4	Halogen-Free caBGA	332	COM
LCMXO2-7000HC-5BG332C	6864	2.5 V / 3.3 V	-5	Halogen-Free caBGA	332	COM
LCMXO2-7000HC-6BG332C	6864	2.5 V / 3.3 V	-6	Halogen-Free caBGA	332	COM
LCMXO2-7000HC-4FG400C	6864	2.5 V / 3.3 V	-4	Halogen-Free fpBGA	400	COM
LCMXO2-7000HC-5FG400C	6864	2.5 V / 3.3 V	-5	Halogen-Free fpBGA	400	COM
LCMXO2-7000HC-6FG400C	6864	2.5 V / 3.3 V	-6	Halogen-Free fpBGA	400	COM
LCMXO2-7000HC-4FG484C	6864	2.5 V / 3.3 V	-4	Halogen-Free fpBGA	484	COM
LCMXO2-7000HC-5FG484C	6864	2.5 V / 3.3 V	-5	Halogen-Free fpBGA	484	COM
LCMXO2-7000HC-6FG484C	6864	2.5 V / 3.3 V	-6	Halogen-Free fpBGA	484	COM

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-1200HC-4TG100CR1 ¹	1280	2.5 V / 3.3 V	-4	Halogen-Free TQFP	100	COM
LCMXO2-1200HC-5TG100CR1 ¹	1280	2.5 V / 3.3 V	-5	Halogen-Free TQFP	100	COM
LCMXO2-1200HC-6TG100CR1 ¹	1280	2.5 V / 3.3 V	-6	Halogen-Free TQFP	100	COM
LCMXO2-1200HC-4MG132CR1 ¹	1280	2.5 V / 3.3 V	-4	Halogen-Free csBGA	132	COM
LCMXO2-1200HC-5MG132CR1 ¹	1280	2.5 V / 3.3 V	-5	Halogen-Free csBGA	132	COM
LCMXO2-1200HC-6MG132CR1 ¹	1280	2.5 V / 3.3 V	-6	Halogen-Free csBGA	132	COM
LCMXO2-1200HC-4TG144CR1 ¹	1280	2.5 V / 3.3 V	-4	Halogen-Free TQFP	144	COM
LCMXO2-1200HC-5TG144CR1 ¹	1280	2.5 V / 3.3 V	-5	Halogen-Free TQFP	144	COM
LCMXO2-1200HC-6TG144CR1 ¹	1280	2.5 V / 3.3 V	-6	Halogen-Free TQFP	144	COM

1. Specifications for the “LCMXO2-1200HC-speed package CR1” are the same as the “LCMXO2-1200HC-speed package C” devices respectively, except as specified in the [R1 Device Specifications](#) section of this data sheet.

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-2000ZE-1UWG49ITR ¹	2112	1.2 V	-1	Halogen-Free WLCSP	49	IND
LCMXO2-2000ZE-1UWG49ITR50 ³	2112	1.2 V	-1	Halogen-Free WLCSP	49	IND
LCMXO2-2000ZE-1UWG49ITR1K ²	2112	1.2 V	-1	Halogen-Free WLCSP	49	IND
LCMXO2-2000ZE-1TG100I	2112	1.2 V	-1	Halogen-Free TQFP	100	IND
LCMXO2-2000ZE-2TG100I	2112	1.2 V	-2	Halogen-Free TQFP	100	IND
LCMXO2-2000ZE-3TG100I	2112	1.2 V	-3	Halogen-Free TQFP	100	IND
LCMXO2-2000ZE-1MG132I	2112	1.2 V	-1	Halogen-Free csBGA	132	IND
LCMXO2-2000ZE-2MG132I	2112	1.2 V	-2	Halogen-Free csBGA	132	IND
LCMXO2-2000ZE-3MG132I	2112	1.2 V	-3	Halogen-Free csBGA	132	IND
LCMXO2-2000ZE-1TG144I	2112	1.2 V	-1	Halogen-Free TQFP	144	IND
LCMXO2-2000ZE-2TG144I	2112	1.2 V	-2	Halogen-Free TQFP	144	IND
LCMXO2-2000ZE-3TG144I	2112	1.2 V	-3	Halogen-Free TQFP	144	IND
LCMXO2-2000ZE-1BG256I	2112	1.2 V	-1	Halogen-Free caBGA	256	IND
LCMXO2-2000ZE-2BG256I	2112	1.2 V	-2	Halogen-Free caBGA	256	IND
LCMXO2-2000ZE-3BG256I	2112	1.2 V	-3	Halogen-Free caBGA	256	IND
LCMXO2-2000ZE-1FTG256I	2112	1.2 V	-1	Halogen-Free ftBGA	256	IND
LCMXO2-2000ZE-2FTG256I	2112	1.2 V	-2	Halogen-Free ftBGA	256	IND
LCMXO2-2000ZE-3FTG256I	2112	1.2 V	-3	Halogen-Free ftBGA	256	IND

1. This part number has a tape and reel quantity of 5,000 units with a minimum order quantity of 10,000 units. Order quantities must be in increments of 5,000 units. For example, a 10,000 unit order will be shipped in two reels with one reel containing 5,000 units and the other reel with less than 5,000 units (depending on test yields). Unserviced backlog will be canceled.
2. This part number has a tape and reel quantity of 1,000 units with a minimum order quantity of 1,000. Order quantities must be in increments of 1,000 units. For example, a 5,000 unit order will be shipped as 5 reels of 1000 units each.
3. This part number has a tape and reel quantity of 50 units with a minimum order quantity of 50. Order quantities must be in increments of 50 units. For example, a 1,000 unit order will be shipped as 20 reels of 50 units each.

High Performance Industrial Grade Devices Without Voltage Regulator, Halogen Free (RoHS) Packaging

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-2000HE-4TG100I	2112	1.2 V	-4	Halogen-Free TQFP	100	IND
LCMXO2-2000HE-5TG100I	2112	1.2 V	-5	Halogen-Free TQFP	100	IND
LCMXO2-2000HE-6TG100I	2112	1.2 V	-6	Halogen-Free TQFP	100	IND
LCMXO2-2000HE-4MG132I	2112	1.2 V	-4	Halogen-Free csBGA	132	IND
LCMXO2-2000HE-5MG132I	2112	1.2 V	-5	Halogen-Free csBGA	132	IND
LCMXO2-2000HE-6MG132I	2112	1.2 V	-6	Halogen-Free csBGA	132	IND
LCMXO2-2000HE-4TG144I	2112	1.2 V	-4	Halogen-Free TQFP	144	IND
LCMXO2-2000HE-5TG144I	2112	1.2 V	-5	Halogen-Free TQFP	144	IND
LCMXO2-2000HE-6TG144I	2112	1.2 V	-6	Halogen-Free TQFP	144	IND
LCMXO2-2000HE-4BG256I	2112	1.2 V	-4	Halogen-Free caBGA	256	IND
LCMXO2-2000HE-5BG256I	2112	1.2 V	-5	Halogen-Free caBGA	256	IND
LCMXO2-2000HE-6BG256I	2112	1.2 V	-6	Halogen-Free caBGA	256	IND
LCMXO2-2000HE-4FTG256I	2112	1.2 V	-4	Halogen-Free ftBGA	256	IND
LCMXO2-2000HE-5FTG256I	2112	1.2 V	-5	Halogen-Free ftBGA	256	IND
LCMXO2-2000HE-6FTG256I	2112	1.2 V	-6	Halogen-Free ftBGA	256	IND

Part Number	LUTs	Supply Voltage	Grade	Package	Leads	Temp.
LCMXO2-2000UHE-4FG484I	2112	1.2 V	-4	Halogen-Free fpBGA	484	IND
LCMXO2-2000UHE-5FG484I	2112	1.2 V	-5	Halogen-Free fpBGA	484	IND
LCMXO2-2000UHE-6FG484I	2112	1.2 V	-6	Halogen-Free fpBGA	484	IND

Date	Version	Section	Change Summary
December 2014	2.9	Introduction	Updated the Features section. Revised Table 1-1, MachXO2 Family Selection Guide. — Removed XO2-4000U data. — Removed 400-ball ftBGA. — Removed 25-ball WLCSP value for XO2-2000U.
		DC and Switching Characteristics	Updated the Recommended Operating Conditions section. Adjusted Max. values for V_{CC} and V_{CCIO} . Updated the sysIO Recommended Operating Conditions section. Adjusted Max. values for LVCMOS 3.3, LVTTTL, PCI, LVDS33 and LVPECL.
		Pinout Information	Updated the Pinout Information Summary section. Removed MachXO2-4000U.
		Ordering Information	Updated the MachXO2 Part Number Description section. Removed BG400 package.
			Updated the High-Performance Commercial Grade Devices with Voltage Regulator, Halogen Free (RoHS) Packaging section. Removed LCMXO2-4000UHC part numbers. Updated the High-Performance Industrial Grade Devices with Voltage Regulator, Halogen Free (RoHS) Packaging section. Removed LCMXO2-4000UHC part numbers.
November 2014	2.8	Introduction	Updated the Features section. — Revised I/Os under Flexible Logic Architecture. — Revised standby power under Ultra Low Power Devices. — Revise input frequency range under Flexible On-Chip Clocking. Updated Table 1-1, MachXO2 Family Selection Guide. — Added XO2-4000U data. — Removed HE and ZE device options for XO2-4000. — Added 400-ball ftBGA.
			Pinout Information
		Ordering Information	Updated the MachXO2 Part Number Description section. Added BG400 package.
			Updated the Ordering Information section. Added MachXO2-4000U caBGA400 and MachXO2-7000 caBGA400 part numbers.
October 2014	2.7	Ordering Information	Updated the Ultra Low Power Industrial Grade Devices, Halogen Free (RoHS) Packaging section. Fixed typo in LCMXO2-2000ZE-1UWG49ITR part number package.
		Architecture	Updated the Supported Standards section. Added MIPI information to Table 2-12. Supported Input Standards and Table 2-13. Supported Output Standards.
		DC and Switching Characteristics	Updated the BLVDS section. Changed output impedance nominal values in Table 3-2, BLVDS DC Condition. Updated the LVPECL section. Changed output impedance nominal value in Table 3-3, LVPECL DC Condition. Updated the sysCONFIG Port Timing Specifications section. Updated INITN low time values.
July 2014	2.6	DC and Switching Characteristics	Updated sysIO Single-Ended DC Electrical Characteristics ^{1,2} section. Updated footnote 4. Updated Register-to-Register Performance section. Updated footnote.
			Ordering Information

Date	Version	Section	Change Summary	
May 2014	2.5	Architecture	Updated TransFR (Transparent Field Reconfiguration) section. Updated TransFR description for PLL use during background Flash programming.	
February 2014	02.4	Introduction	Included the 49 WLCSP package in the MachXO2 Family Selection Guide table.	
		Architecture	Added information to Standby Mode and Power Saving Options section.	
		Pinout Information	Added the XO2-2000 49 WLCSP in the Pinout Information Summary table.	
		Ordering Information	Added UW49 package in MachXO2 Part Number Description. Added and LCMXO2-2000ZE-1UWG49CTR in Ultra Low Power Commercial Grade Devices, Halogen Free (RoHS) Packaging section. Added and LCMXO2-2000ZE-1UWG49ITR in Ultra Low Power Industrial Grade Devices, Halogen Free (RoHS) Packaging section.	
December 2013	02.3	Architecture	Updated information on CLKOS output divider in sysCLOCK Phase Locked Loops (PLLs) section.	
		DC and Switching Characteristics	Updated Static Supply Current – ZE Devices table. Updated footnote 4 in sysIO Single-Ended DC Electrical Characteristics table; Updated V_{IL} Max. (V) data for LVCMOS 25 and LVCMOS 28.	
			Updated V_{OS} test condition in sysIO Differential Electrical Characteristics - LVDS table.	
September 2013	02.2	Architecture	Removed I ² C Clock-Stretching feature per PCN #10A-13. Removed information on PDPR memory in RAM Mode section. Updated Supported Input Standards table.	
			DC and Switching Characteristics	Updated Power-On-Reset Voltage Levels table.
			June 2013	02.1
DC and Switching Characteristics	Added slew rate information to footnote 2 of the MachXO2 External Switching Characteristics – HC/HE Devices and the MachXO2 External Switching Characteristics – ZE Devices tables. Power-On-Reset Voltage Levels table – Added symbols.			